

Application/Control No.	Applicant(s)/Patent under Reexamination VAN DE BEEK ET AL.	
10/525,862		
Examiner	Art Unit	
Ryan C. Jager	2816	

SEARCHED					
Class	Subclass	Date	Examiner		
327	147	5-15-06	RES		
327		5-15-06	br2		
327 update	above	10-52-06	RUJ		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
PG-Pi	B	1/4/07	Res.	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Imuted text search (see notes)	5.16-06	RES
tent search (see notes)	5-16-06	RCJ
test search (see notes)	5-17-06	pc5
textscarch	5-17-06	RCZ
(see votes) update above	1925/06	RCJ
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